Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,203	LI ET AL.	
Examiner	Art Unit	
Sam K. Ahn	2611	

SEARCHED					
375	261,298, 316,320	8/28	a		
329	304, 347, 348, 349				
332.	348,349 103,120, 149,150				
370	207	9/29	a		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST inventor search keyword & citation search IEEE & Google keyword & citation search		an			
Consulted John leng & M. Ghayaut & Reinhard Fixen 20pf on 101 issues Consulted Khai Tran 375 P. F. & Young Tre 375 P. F.	9/29	a.			